

Search Notes

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Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

HAGIWARA ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	6/6/2007	AW

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR